Freeform Search

US Pre-Grant Publication Full-Text Database US Patents Full-Text Database US OCR Full-Text Database Database: EPO Abstracts Database JPO Abstracts Database **Derwent World Patents Index IBM** Technical Disclosure Bulletins (near-field microscope) and (metal tip or metal point or metal member or metal probe) Term: Documents in Display Format: - Starting with Number 1 Display: Generate: O Hit List O Hit Count O Side by Side O Image Search Interrupt Clear *

Search History

DATE: Friday, December 10, 2004 Printable Copy Create Case

Set Name side by side	Query	<u>Hit</u> Count	Set Name result set
DB=B	PGPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=ADJ		
<u>L7</u>	(near-field microscope) and (metal tip or metal point or metal member or metal probe)	5	<u>L7</u>
DB=B	PGPB, USPT, USOC, EPAB, JPAB; PLUR=YES; OP=ADJ		
<u>L6</u>	L3 and (polarizati\$4)	54	<u>L6</u>
<u>L5</u>	L3 and (metal member or metal point or metal tip or metal end)	14	<u>L5</u>
<u>L4</u>	L3 and (planar substrate or flat substrate)	22	<u>L4</u>
<u>L3</u>	L2 and (light source or laser or light beam)	248	<u>L3</u>
<u>L2</u>	L1 and "near-field"	294	<u>L2</u>
<u>L1</u>	(250/216,234,306,307,225,559.09;73/105;359/321,738)![CCLS]	8575	<u>L1</u>

END OF SEARCH HISTORY